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Surface chemical analysis — Depth profiling — Methods for ion beam alignment and the associated measurement of current or current density for depth profiling in AES and XPS

Analyse chimique des surfaces — Profilage d'épaisseur — Méthodes d'alignement du faisceau d'ions et la mesure associée de densité de courant ou de courant pour le profilage d'épaisseur en AES et XPS

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Foreword

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This document was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 4, *Depth profiling*.

This second edition cancels and replaces the first edition (ISO 16531:2013), which has been technically revised.

The main changes to the previous edition are as follows:

- Table 1, in reference to 5.4: a comment has been added to mention the use of automated alignment routine.
- 5.3.2, 5.3.3 and 5.5.4: some descriptions in notes have been changed to body text.
- minor editorial changes have been introduced for clarity.

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